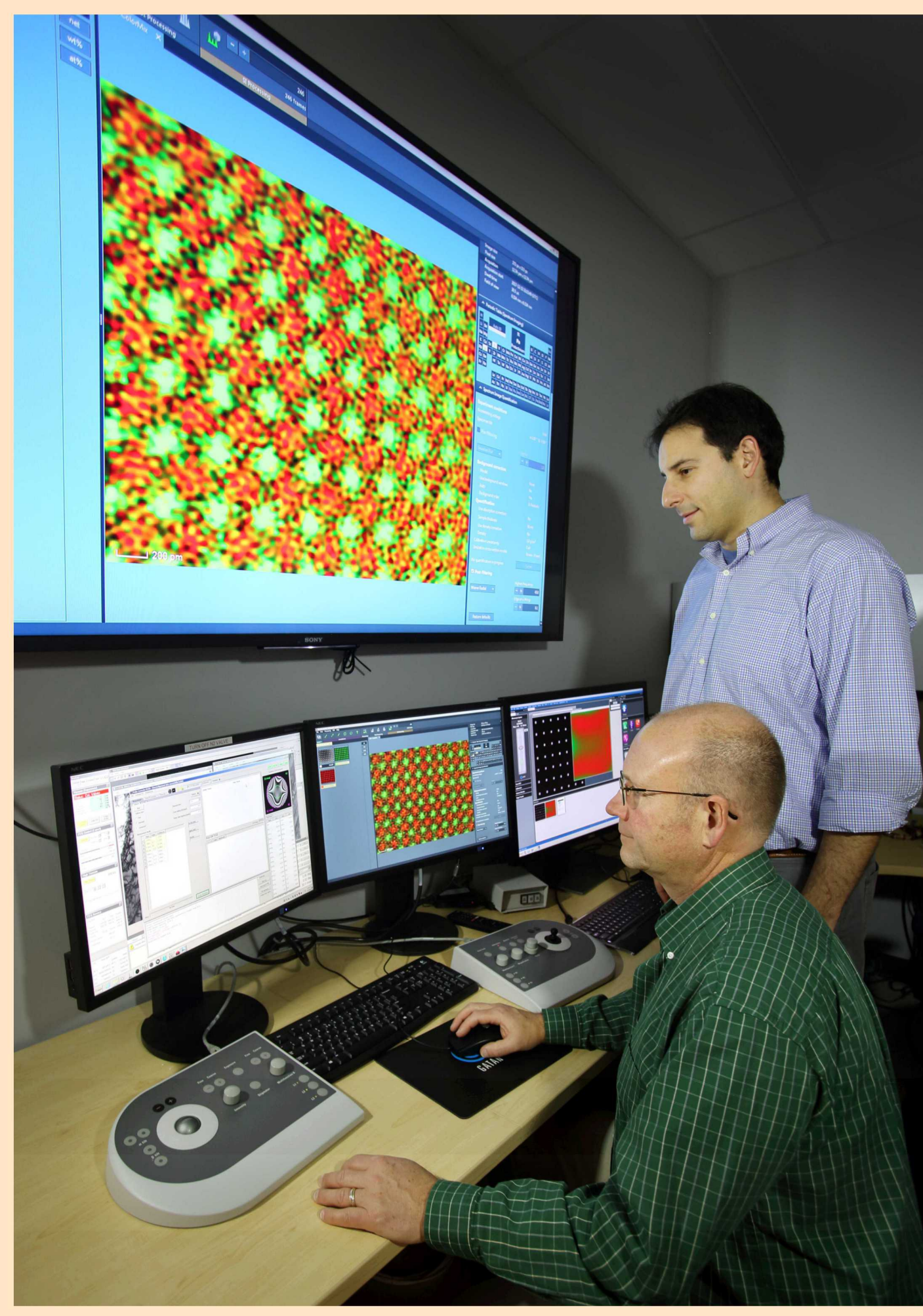
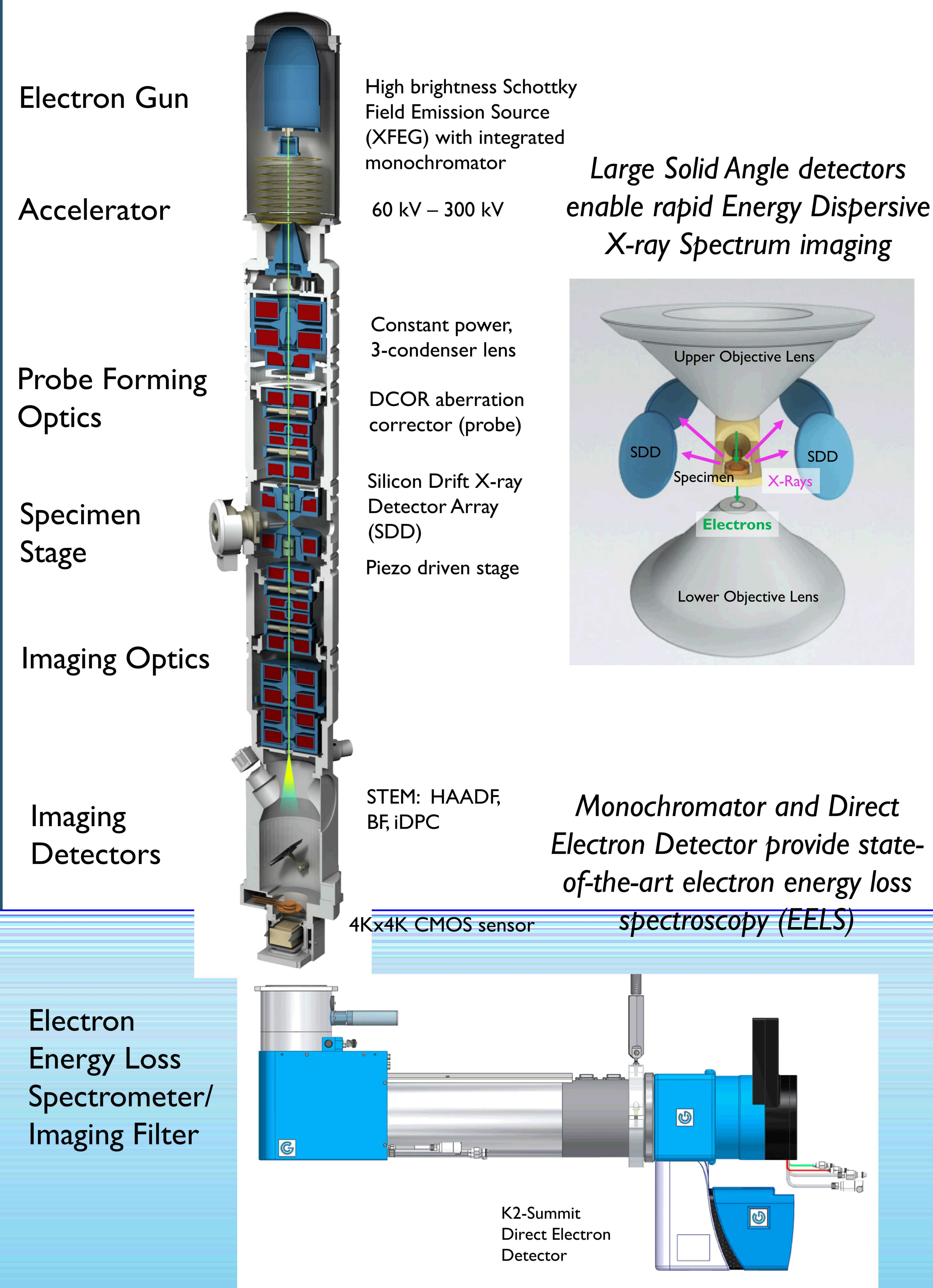




Themis Z Scanning Transmission Electron Microscope: Advanced capabilities for atomic to micron-scale characterization



Sandia's Themis Z STEM is a state-of-the-art Scanning/Transmission Electron Microscope used for characterization of structure, composition, and bonding of materials over length-scales ranging from atomic dimensions to tens of microns. This probe-corrected and monochromated instrument operates over electron acceleration voltages of 60 kV to 300 kV and includes advanced detectors for imaging, energy dispersive x-ray spectroscopy, and electron energy loss spectroscopy. The instrument is equipped with a variety of specimen holders for high quality analytical measurements, tomographic analyses, and *in situ* experiments.



Extensive Facilities Modifications Provide Stable Environment for Advanced Microscopy Laboratory designed to meet tight environmental tolerances

- Separate control room to minimize user-induced vibrations and thermal fluctuations.
- Acoustic shielding to suppress ambient noise.
- Rework of air handling and temperature control systems to meet thermal and airflow requirements.
- Redesign of electrical systems and installation of active field cancellation system to meet strict magnetic field requirements.

Close collaboration between facilities, procurement, and S&T community

- Acquisition, design, construction, and installation completed over accelerated 8-month schedule.

